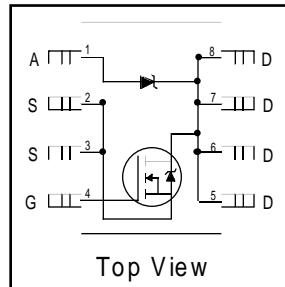


**FETKY™ MOSFET & Schottky Diode**

- Co-packaged HEXFET® Power MOSFET and Schottky Diode
- Ideal For Synchronous Regulator Applications
- Generation V Technology
- SO-8 Footprint

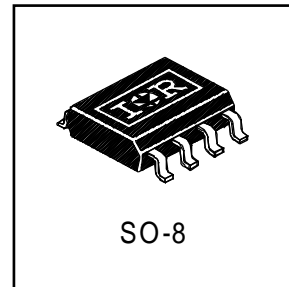


$V_{DSS} = 30V$   
 $R_{DS(on)} = 0.035\Omega$   
 Schottky  $V_f = 0.42V$

## Description

The FETKY™ family of co-packaged HEXFETs and Schottky diodes offer the designer an innovative board space saving solution for switching regulator applications. Generation 5 HEXFETs utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. Combining this technology with International Rectifier's low forward drop Schottky rectifiers results in an extremely efficient device suitable for use in a wide variety of portable electronics applications.

The SO-8 has been modified through a customized leadframe for enhanced thermal characteristics. The SO-8 package is designed for vapor phase, infra red or wave soldering techniques.



## Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^{**}$	6.4	A
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^*$	4.1	
$I_D @ T_A = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^*$	3.3	
$I_{DM}$	Pulsed Drain Current ①	33	
$P_D @ T_A = 25^\circ C$	Power Dissipation (PCB Mount)**	2.5	W
$P_D @ T_A = 25^\circ C$	Power Dissipation (PCB Mount)*	1.0	W
	Linear Derating Factor (PCB Mount)*	8.0	mW/°C
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$T_J, T_{STG}$	Junction and Storage Temperature Range	-55 to + 150	°C

## Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JA}$	Junction-to-Amb. (PCB Mount, steady state)*	100	125	°C/W
$R_{\theta JA}$	Junction-to-Amb. (PCB Mount, steady state)**	40	50	
$R_{\theta JA}$	Junction-to-Amb. _Schottky *	100	125	

### Notes:

① Repetitive rating – pulse width limited by max. junction temperature (see fig. 11)

②  $I_{SD} \leq 4.1A$ ,  $di/dt \leq 110A/\mu s$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq 150^\circ C$

③ Pulse width  $\leq 300\mu s$  – duty cycle  $\leq 2\%$

\* When mounted on FR-4 board using minimum recommended footprint.

\*\* When mounted on 1 inch square copper board, for comparison with other SMD devices.

## MOSFET Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	30	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	—	0.035	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 4.1A ③
		—	—	0.060		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 2.1A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0	—	—	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
g <sub>fs</sub>	Forward Transconductance	4.6	—	—	S	V <sub>DS</sub> = 15V, I <sub>D</sub> = 2.1A
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	1.0	μA	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V
		—	—	25		V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	—	—	-100	nA	V <sub>GS</sub> = -20V
	Gate-to-Source Reverse Leakage	—	—	100		V <sub>GS</sub> = 20V
Q <sub>g</sub>	Total Gate Charge	—	18	27	nC	I <sub>D</sub> = 4.1A
Q <sub>gs</sub>	Gate-to-Source Charge	—	2.2	3.3		V <sub>DS</sub> = 24V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	—	5.9	8.9		V <sub>GS</sub> = 10V, See Fig. 6 and 9 ③
t <sub>d(on)</sub>	Turn-On Delay Time	—	6.7	—		V <sub>DD</sub> = 15V
t <sub>r</sub>	Rise Time	—	27	—	ns	I <sub>D</sub> = 4.1A
t <sub>d(off)</sub>	Turn-Off Delay Time	—	20	—		R <sub>G</sub> = 6.2Ω
t <sub>f</sub>	Fall Time	—	16	—		R <sub>D</sub> = 3.7Ω, See Fig. 10 ③
C <sub>iss</sub>	Input Capacitance	—	510	—		V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance	—	200	—	pF	V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance	—	84	—		f = 1.0MHz, See Fig. 5

## MOSFET Source-Drain Ratings and Characteristics

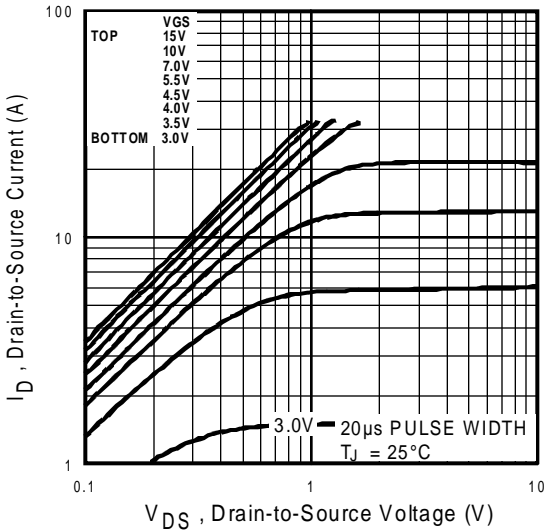
	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	1.3	A	T <sub>J</sub> = 25°C, I <sub>S</sub> = 4.1A, V <sub>GS</sub> = 0V
I <sub>SM</sub>	Pulsed Source Current (Body Diode)	—	—	33		
V <sub>SD</sub>	Body Diode Forward Voltage	—	—	1.0	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 4.1A, V <sub>GS</sub> = 0V
t <sub>rr</sub>	Reverse Recovery Time (Body Diode)	—	57	86	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 4.1A
Q <sub>rr</sub>	Reverse Recovery Charge	—	93	140	nC	di/dt = 100A/μs ③

## Schottky Diode Maximum Ratings

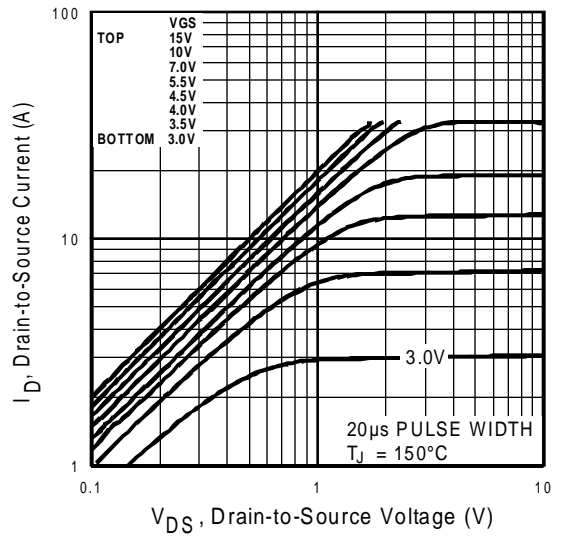
	Parameter	Max.	Units	Conditions
I <sub>f</sub> (av)	Max. Average Forward Current	2.0	A	50% Duty Cycle. Rectangular Wave, T <sub>c</sub> = 132°C
		4.0		50% Duty Cycle. Rectangular Wave, T <sub>c</sub> = 117°C
I <sub>SM</sub>	Max. peak one cycle Non-repetitive Surge current	150	A	5μs sine or 3μs Rect. pulse
		15		10ms sine or 6ms Rect. pulse
				Following any rated load condition & with V <sub>rrm</sub> applied

## Schottky Diode Electrical Specifications

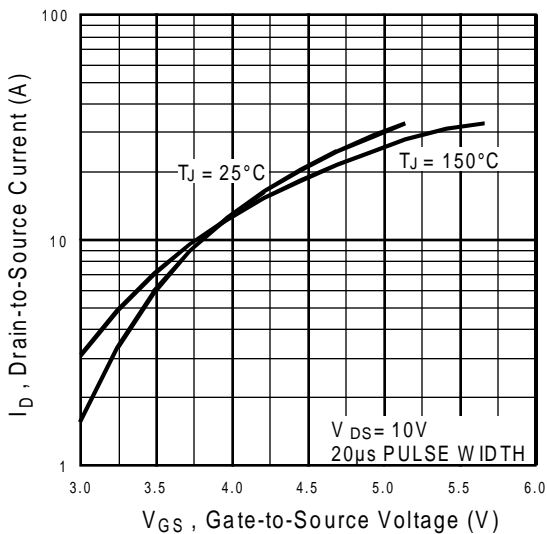
	Parameter	Max.	Units	Conditions
V <sub>fm</sub>	Max. Forward voltage drop	0.50	V	I <sub>f</sub> = 1.0, T <sub>J</sub> = 25°C
		0.60		I <sub>f</sub> = 2.0, T <sub>J</sub> = 25°C
		0.42		I <sub>f</sub> = 1.0, T <sub>J</sub> = 125°C
		0.55		I <sub>f</sub> = 2.0, T <sub>J</sub> = 125°C
I <sub>rm</sub>	Max. Reverse Leakage current	0.10	mA	V <sub>r</sub> = 30V, T <sub>J</sub> = 25°C
		15		T <sub>J</sub> = 125°C
C <sub>t</sub>	Max. Junction Capacitance	100	pF	V <sub>r</sub> = 5Vdc ( 100kHz to 1 MHz) 25°C
dv/dt	Max. Voltage Rate of Charge	5200	V/ μs	Rated V <sub>r</sub>



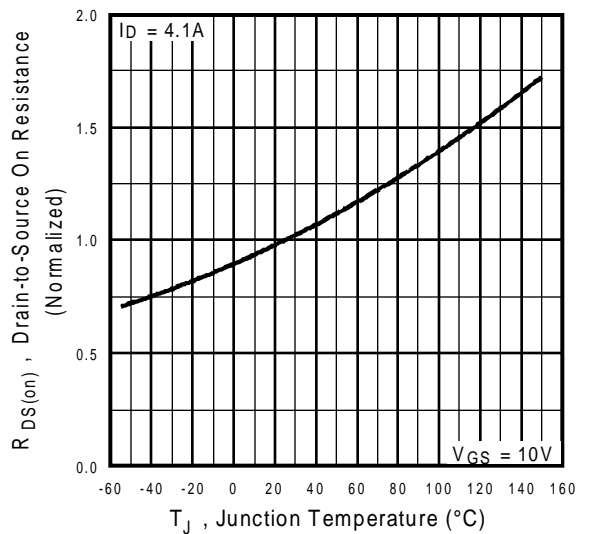
**Fig 1.** Typical Output Characteristics,  
 $T_J = 25^\circ\text{C}$



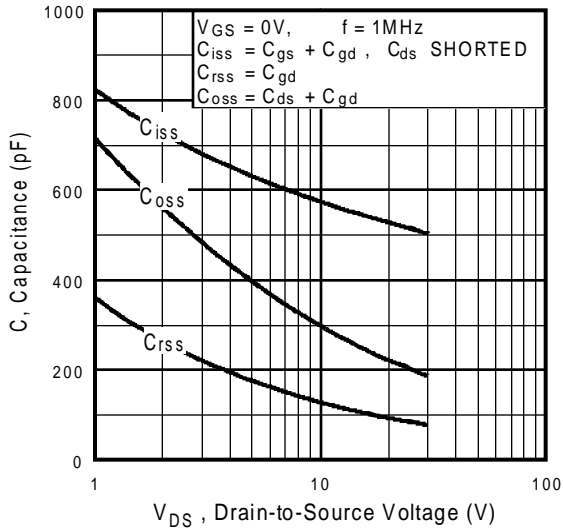
**Fig 2.** Typical Output Characteristics,  
 $T_J = 150^\circ\text{C}$



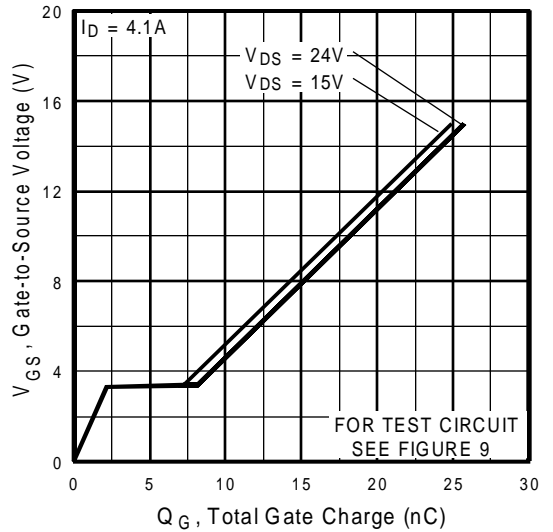
**Fig 3.** Typical Transfer Characteristics



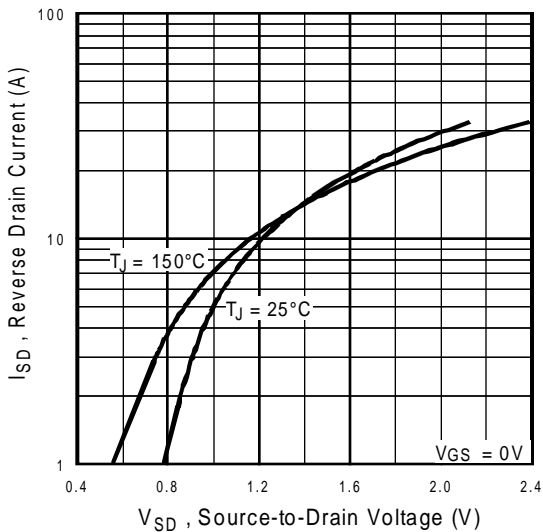
**Fig 4.** Normalized On-Resistance  
Vs. Temperature



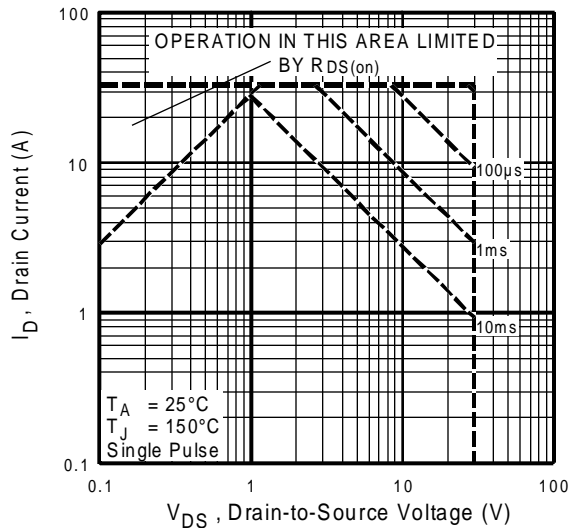
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



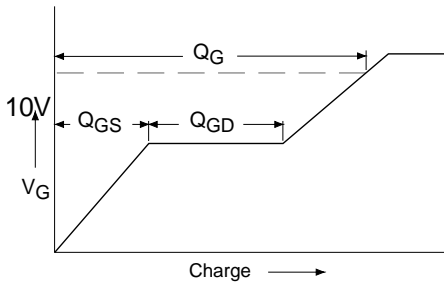
**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



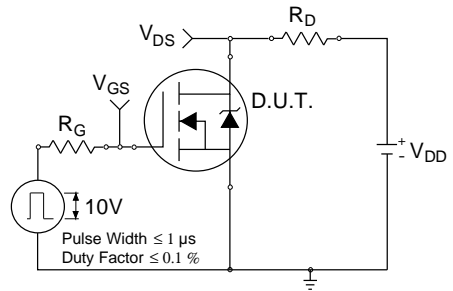
**Fig 7.** Typical Source-Drain Diode Forward Voltage



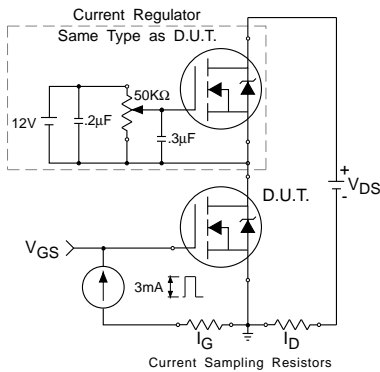
**Fig 8.** Maximum Safe Operating Area



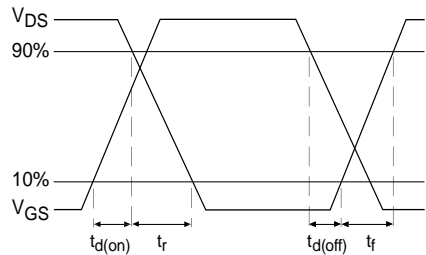
**Fig 9a.** Basic Gate Charge Waveform



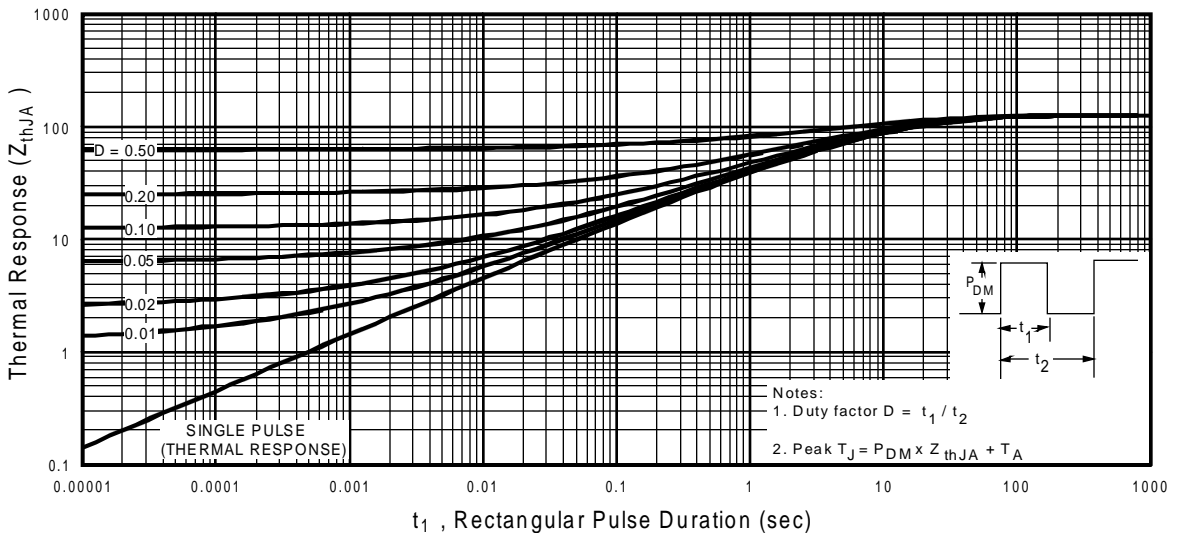
**Fig 10a.** Switching Time Test Circuit



**Fig 9b.** Gate Charge Test Circuit



**Fig 10b.** Switching Time Waveforms



**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

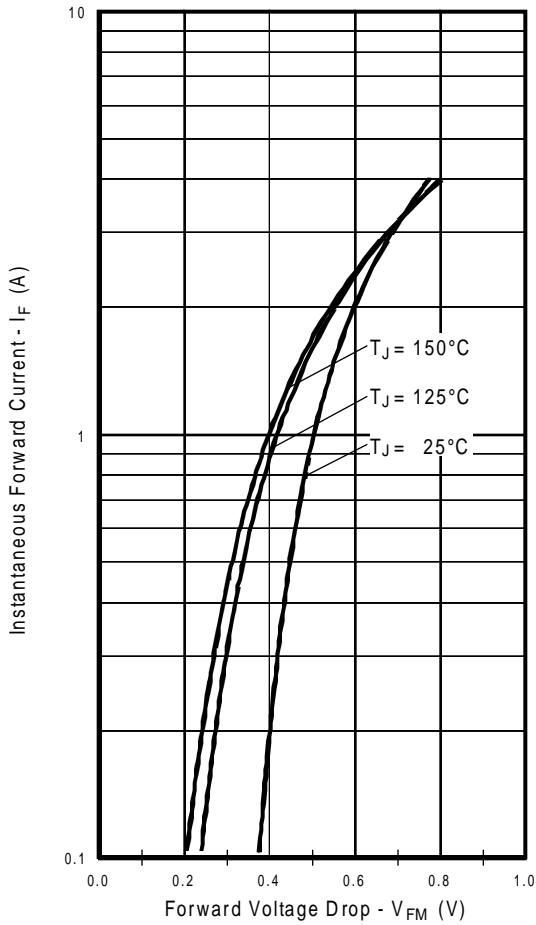


Fig. 12 - Max. Forward Voltage Drop Characteristics

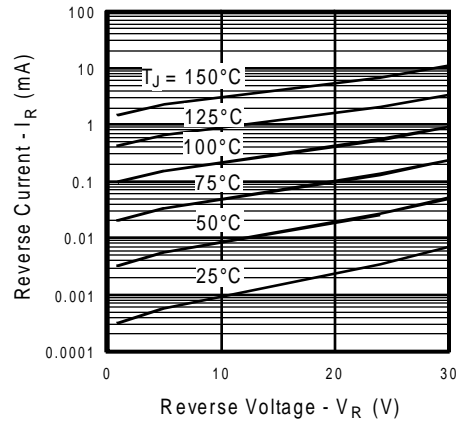


Fig. 13 - Typical Values of Reverse Current Vs. Reverse Voltage

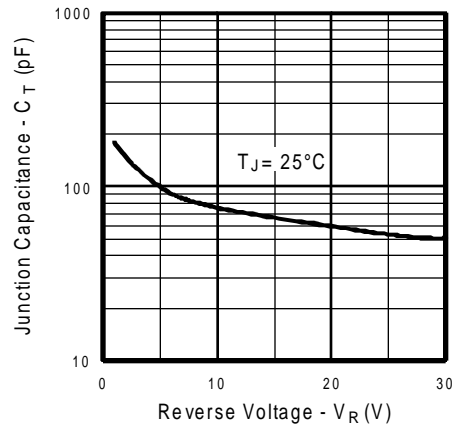
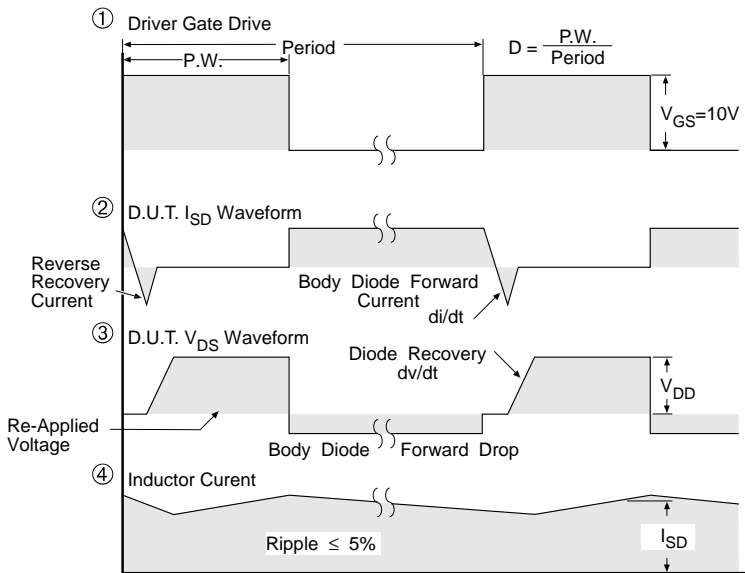
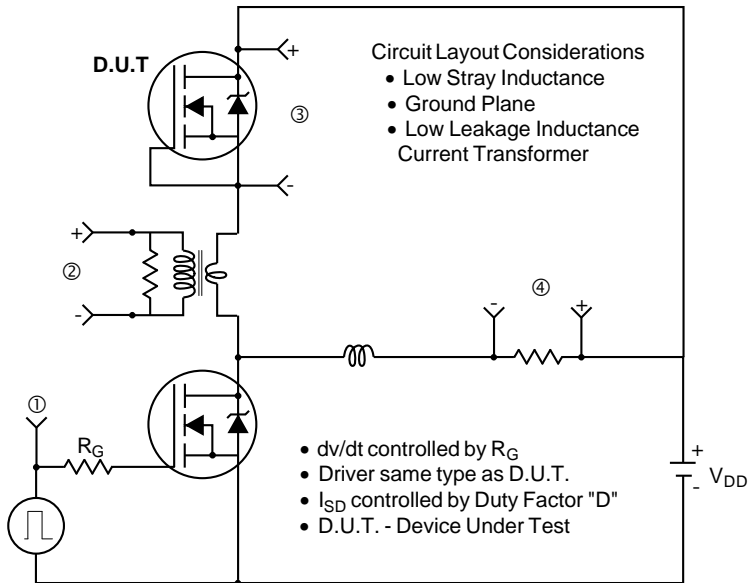


Fig. 14 - Typical Junction Capacitance Vs. Reverse Voltage

## Peak Diode Recovery $dv/dt$ Test Circuit



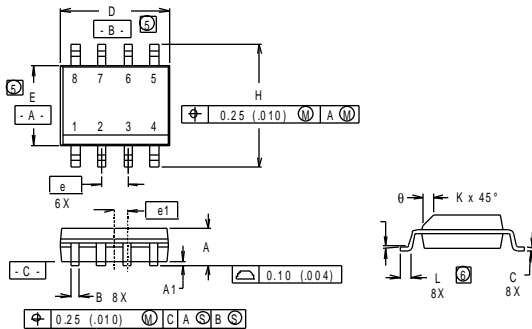
\*  $V_{GS} = 5V$  for Logic Level Devices

**Fig 20.** For N-Channel HEXFETS

# IRF7421D1

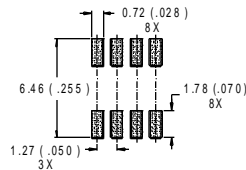


## SO-8 Package Details



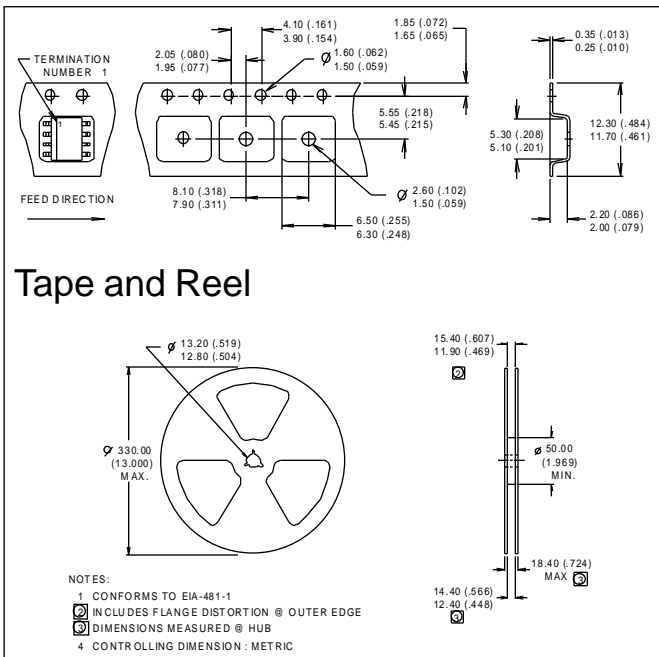
DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
B	.014	.018	0.36	0.46
C	.0075	.0098	0.19	0.25
D	.189	.196	4.80	4.98
E	.150	.157	3.81	3.99
e	.050 BASIC		1.27 BASIC	
e1	.025 BASIC		0.635 BASIC	
H	.2284	.2440	5.80	6.20
K	.011	.019	0.28	0.48
L	0.16	.050	0.41	1.27
θ	0°	8°	0°	8°

RECOMMENDED FOOTPRINT



NOTES:

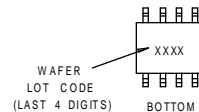
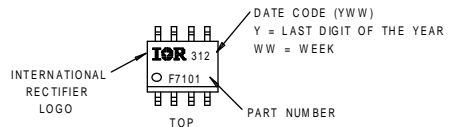
1. DIMENSIONING AND TOLERANCING PER ANSIS Y14.5M-1982.
2. CONTROLLING DIMENSION: INCH.
3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
5. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 (0.006).
6. DIMENSIONS IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE..



NOTES:

1. CONFORMS TO EIA-481-1
2. INCLUDES FLANGE DISTORTION @ OUTER EDGE
3. DIMENSIONS MEASURED @ HUB
4. CONTROLLING DIMENSION: METRIC

## Part Marking (IRF7101 example)



**WORLD HEADQUARTERS:** 233 Kansas St., El Segundo, California 90245, Tel: (310) 322 3331  
**EUROPEAN HEADQUARTERS:** Hurst Green, Oxted, Surrey RH8 9BB, UK Tel: (44) 0883 713215  
**IR CANADA:** 7321 Victoria Park Ave., Suite 201, Markham, Ontario L3R 3L1, Tel: (905) 475 1897 **IR GERMANY:** Saalburgstrasse 157, 61350 Bad Homburg Tel: 6172 37066 **IR ITALY:** Via Liguria 49, 10071 Borgaro, Torino Tel: (39) 1145 10111 **IR FAR EAST:** K&H Bldg., 2F, 3-30-4 Nishi-Ikeburo 3-Chome, Toshima-Ki, Tokyo 171 Tel: (03)3983 0641 **IR SOUTHEAST ASIA:** 315 Outram Road, #10-02 Tan Boon Liat Building, Singapore 0316 Tel: 65 221 8371  
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